

*Abstract*

The invention relates to a process to examine at least one object, whereby properties of the object are detected at different times within a spatial-frequency space formed by spatial frequencies.

According to the invention, the process is carried out in such a way that consecutive images are recorded in overlapping areas of the spatial-frequency space and, additionally, in areas of the spatial-frequency space that differ from each other.

*List of reference numerals:*

- 1        central area
- 10      additional areas of the spatial-frequency space
- 20      additional areas of the spatial-frequency space
- 30      additional areas of the spatial-frequency space